Electronic Supplementary Information

Boosting photocatalytic performance of Cd_xZn_{1-x}S for H₂ production

by Mo₂C MXene with large interlayer distance

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Experiment S1

Determination of the optimal ratio of Cd and Zn in Cd_xZn_{1-x}S solid solution.

4 mmol of Cd(NO₃)₂·4H₂O (Macklin, Shanghai, China, AR 99%) and Zn(NO₃)₂·6H₂O (Fengchuan Chemical Reagent Technology Co., LTD, Tianjin, China, AR 99%) was dissolved in 20 mL de-ionized water to form mixed cadmium and zinc source solution. Then 4 mmol of (NH₄)₂S (Aladdin, Shanghai, China, AR 20% in H₂O) solution was diluted in 20 mL de-ionized water to provide sulfur source. Thereafter, the (NH₄)₂S aqueous solution was added dropwise into the above mixed solution with stirring at room temperature. After 1 h chemical reaction, the precipitate was centrifuged and washed by de-ionized water and ethanol until pH≈7, followed by drying in vacuum at 60 °C overnight. At last, the block samples with different color were added successively in a mortar and grinded thoroughly using a pestle until a homogenous powder. According to molar ratio of Cd and Zn, the amount of Cd(NO₃)₂ and Zn(NO₃)₂ is based on the formula of Cd_xZn_{1-x}S (x = 0.1, 0.2, 0.3, ..., 0.9), and the corresponding CZS samples were labeled as Cd_{0.1}Zn_{0.9}S, Cd_{0.2}Zn_{0.8}S, Cd_{0.3}Zn_{0.7}S, Cd_{0.4}Zn_{0.6}S, Cd_{0.5}Zn_{0.5}S, Cd_{0.6}Zn_{0.4}S, Cd_{0.7}Zn_{0.3}S, Cd_{0.6}Zn_{0.2}S and Cd_{0.9}Zn_{0.1}S.

Experiment S2

Physicochemical characterizations.

The component of all the samples were tested by X-ray diffraction (XRD; Smartlab, Rigaku Corporation, Japan) using Cu-K_{α} (λ =1.5406 Å) radiation at a scan rate of $0.02 \ 2\theta \ s^{-1}$. The microstructures were observed by scanning electron microscopy (SEM; Merlin Compact, Zeiss, Germany) equipped with an energy disperse spectroscope (EDS; X-MaxN, Oxford, UK) and transmission electron microscope (TEM, 2100F, JEM, Japan) with an accelerating voltage of 200 kV. The powder size distribution was tested by a particle size analyzer via wet process (Mastersizer 3000, Malvern, UK). The surface chemical element composition and chemical states of the samples were characterized by an X-ray photoelectron spectrometer (XPS, ESCALAB 250X, ThermoFischer, USA). The spectra were excited by Al K_{α} source (hv=1486.6 eV, operated at 12.5 kV with heater current of 16 mA) with a passing-energy of 100 eV for survey spectra and 20 eV for high-resolution spectra at a step size of 0.05 eV. The Brunauer-Emmett-Teller (BET) specific surface area (SSA) of the samples were investigated by N₂ adsorption-desorption at 77 K using a Micromeritics ASAP2460 adsorption analyzer and the SSA was determined by a multipoint BET method utilizing the adsorption data in the range of relative pressure (P/P_0) of 0.05-0.3. All the samples were pretreated by degassing at 80°C in vacuum before N₂ adsorption measurements. The ultraviolet-visible (UV-Vis) diffuse reflectance spectra were tested by dry-pressing disk samples with an ultraviolet-visible spectrophotometer (UH4150, Hitachi, Japan) and using BaSO₄ as the reflectance standard in the spectral range of 200-800 nm. The photoluminescence (PL) spectra were measured by a spectrofluorophotometer (Fluoromax-4, Horiba, Japan) under the excitation of 375 nm at room temperature to evaluate the ability of photogenerated carriers.

Experiment S3

Electrochemical and photoelectrochemical measurements.

Photoelectrochemical experiments were carried out by an electrochemical analyzer (Autolab RDE-2, Metrohm, Switzerland) in a standard three-electrode system using the samples as the working electrodes, Ag/AgCl as a reference electrode and the Pt wire as the counter electrode. The transient photocurrent (TPC) measurements were tested under visible light irradiation ($\lambda \ge 420$ nm) with on/off switches at a bias of 0.2 V (vs. Ag/AgCl). The electrochemical impedance spectra (EIS) experiments were performed at an amplitude of 0.01 V (vs. Ag/AgCl) and over the frequency ranges from 100 kHz to 0.1 Hz under visible light irradiation ($\lambda \ge 420$ nm). The Mott-Schottky plots were recorded over the AC frequencies of 500, 800 and 1000 Hz in the dark. The electrolyte in all the electrochemical measurements was 0.5 M Na₂SO₄ aqueous solution. Before the preparation of working electrodes, all the FTO glass plates (1 cm \times 2.5 cm) were washed with acetone, de-ionized water and ethanol, respectively, by ultrasonication for 30 min. The working electrodes of Mo₂C MXene and CZS/Mo₂C samples were prepared as follows: 10 mg of as-prepared samples were dispersed in mixture (400 µL de-ionized water, 100 µL ethanol, 100 µL Nafion for MXenes and 500 µL ethanol, 100 µL Nafion for CZS/Mo₂C samples), followed by ultrasonication for 2 h to make uniform slurries. Thereafter, 100 µL of the slurry was coated onto a FTO glass plate and dried in air for whole night. The work area of the working electrode immersed in the electrolyte was 1 cm^2 .



Fig. S1 (a) The photocatalytic activities of $Cd_xZn_{1-x}S$ samples before hydrothermal treatments under visible-light illumination. XRD patterns of (b) $Cd_{0.8}Zn_{0.2}S$ before (black pattern) and after (green pattern) hydrothermal treatments, (c) pure CdS, ZnS and $Cd_{0.8}Zn_{0.2}S$ after hydrothermal treatments. The dotted lines in (c) display the position of peaks of $Cd_{0.8}Zn_{0.2}S$.

As shown in Fig. S1b, the main crystal composition of $Cd_{0.8}Zn_{0.2}S$ is sphalerite phase because the starting materials are used for chemical reaction at room temperature. After hydrothermal treatment in ethylenediamine, the (111) peak of sphalerite $Cd_{0.8}Zn_{0.2}S^1$ transformed into one sharp and intense (002) peak with two shoulder peaks at 25.2 and 28.6°, which implied the highly crystalline nature. These arisen diffraction peaks, also including the peaks from 45 to 53°, distinctly reveal that the conversion of crystal phase (from sphalerite to wurtzite) can be achieved by the method mentioned in this paper. Since the Cd content in $Cd_{0.8}Zn_{0.2}S$ is dominant, compared with pure CdS synthesized in this paper after hydrothermal treatment in Fig. S1c, all the characteristic peaks of $Cd_{0.8}Zn_{0.2}S$ show a slight shift toward higher degrees with a decreased interplanar spacing, which is attributed to Zn^{2+} ions doping into CdS and the formation of solid solution.²



Fig. S2 SEM images of (a) raw Mo_2Ga_2C and (b) Mo_2C MXene prepared by common etching method.



Fig. S3 SEM image of sphalerite CZSMx sample.



Fig. S4 (a) High resolution XPS spectrum of Ga 2p region for Mo_2C -CTAB. (b) The full-scale XPS spectra of CdS, ZnS and $Cd_{0.8}Zn_{0.2}S$ before and after coupling with Mo_2C -CTAB. (c) The survey spectra of $Cd_{0.8}Zn_{0.2}S$ and CZSM20 focusing on the binding energy range from 215 to 240 eV, showing the existence of peak of Mo 3d.

Supplementary Note 1

The discussion about the negligible existence of Ga₂O₃ in Mo₂C-CTAB.

At the beginning of synthesizing Mo₂Ga₂C, β -Mo₂C powders were mixed with molten Ga in air. The vacuum-sealing process may not be perfect during heating the starting materials at high temperature. Besides, some characterization processes, such as XRD, were also handled in air. As a result, the inevitable contacting with air leads to the generation of Ga₂O₃, thereby coexisting with Mo₂Ga₂C. Similar phenomenon can be found in the preparation of Ti₃AlC₂ with negligible Al₂O₃ impurity.³ The formed Ga₂O₃ has more chemical stability than Ga in acid solution, resulting in incomplete removal of Ga₂O₃ during etching process. Therefore, a little Ga₂O₃ coexist with Mo₂C-CTAB during the subsequent experiments.



Fig. S5 N_2 adsorption-desorption isotherms (a) and pore size distribution curves (b) of $Cd_{0.8}Zn_{0.2}S$, CZSM1, CZSM10 and CZSM20.

Samples	SSA (m ² g ⁻¹)	Pore Volume (cm ³ g ⁻¹)	Average pore diameter (nm)
Cd _{0.8} Zn _{0.2} S	45.5	0.18	17.0
CZSM1	45.1	0.18	16.9
CZSM2.5	40.0	0.16	17.9
CZSM5	40.7	0.15	16.7
CZSM10	37.6	0.15	16.4
CZSM15	40.6	0.16	15.7
CZSM20	38.2	0.15	16.9
CZSM25	38.0	0.15	16.0

Tab. S1 SSA, pore volume and average pore diameter of samples.

Tab. S2 Comparison of AQE values of samples.

Samples	AQE values (%)
$Cd_{0.8}Zn_{0.2}S$	2.5
CZSM1	9.1
CZSM2.5	10.3
CZSM5	13.8
CZSM10	15.6
CZSM15	19.8
CZSM20	22.5
CZSM25	20.6



Fig. S6 (a) XRD patterns of CZSM20 before and after cycling tests. (b) SEM image of CZSM20 after cycling test.



Fig. S7 The UV-Vis diffuse reflectance spectra of CZSMx samples.

Tab. S3 Com	parison of PL	decay time (τ)	and the	correspond	ing relative	amplitude (f)
of Cc	$l_{0.8}Zn_{0.2}S$ and C	CZSM20 teste	d by time	-resolved I	PL spectrosc	opy.

	Decay time (ns)		Relative am	plitude (%)	Average	2
Samples	τ_1	τ_2	\mathbf{f}_1	f_2	lifetime (τ, ns)*	χ²
Cd _{0.8} Zn _{0.2} S	1.0457	5.4716	39.15	60.85	3.73	1.2832
CZSM20	1.9630	8.1575	47.02	52.98	5.24	1.2277

* The average lifetime of carriers is calculated by the equation: $\tau=\tau_1f_1+\tau_2f_2$

 χ^2 : The goodness of fit parameter.



Fig. S8 Nyquist plots (a) and TPC responses (b) of Mo₂C-CTAB and Mo₂C-Br. The inset in (a) is their OCP versus time curves.

Supplementary Note 2

Analysis of photoelectrodes kinetic properties of MXenes.

EIS was used to check the kinetic properties of Mo₂C-CTAB and Mo₂C-Br on asprepared photoelectrodes over different frequency of AC voltage. Fig. S7a compares the Nyquist plots of two MXenes as electrode materials. The two plots are composed of a semicircle with large curvature in high and medium frequency regions, while a linear tendency in low frequency regions. It can be seen clearly that Mo₂C-CTAB has a smaller diameter of semicircle than that of Mo₂C-Br, which distinctly reveals that Mo₂C MXene etched by CTAB possesses better charge-transfer efficiency with weak transfer impedance as compared to Mo₂C MXene prepared by NH₄Br. In general, the changing process of open circuit potential (OCP) versus time reflects the status of the electrode from instability to stability. From the OCP curves in the inset (Fig. S7a), Mo₂C-CTAB has a smaller slope, indicating the photoelectrode of Mo₂C-CTAB can faster achieve the stability in the same time and the variation range of OCP value of Mo₂C-CTAB is smaller. The Warburg impedance,⁴ displayed in the low frequency region, can reflects the solid-state diffusion ability of carriers in the bulk materials. As shown in Fig. S7a, the Mo₂C-CTAB photoelectrode exhibits a Warburg impedance that is almost perpendicular to the x axis, suggesting that the interlayer spacing of Mo₂C flakes connected by CTA⁺ is beneficial to the diffusion and transfer of photongenerated carriers between the layers.



Fig. S9 Mott-Schottky plots of: (a) pure CdS, ZnS and $Cd_{0.8}Zn_{0.2}S$, (b) CZSM20 and CZSM-Br. All these Mott-Schottky values were tested over AC frequency of 1000 Hz.



Fig. S10 The XPS spectrum of Mo₂C-CTAB for O 1s.

Supplementary Note 3

Discussion of the Fermi level of Mo₂C-CTAB.

According to the previous theoretical calculation,⁵ the Fermi level of O-terminated Mo_2C MXene is calculated to be 1.09 V vs. NHE. To check the -O content on the surface of Mo_2C -CTAB, the high-resolution XPS spectrum in O 1s region was tested and shown in Fig. S10. The peaks at 531.0 and 532.0 eV can be assigned, respectively, to $Mo_2C(OH)_x$ (OH-termination) and Mo_2CO_x (O-termination).⁶ It is worth noting that only ~20 at.% of -OH species in O 1s region was detected, indicating most O-terminations was converted from OH-terminations by losing the H⁺ during etching process and more CTA⁺ could be adsorbed in the interlayer spacing. Thus O-terminated Mo_2C -CTAB is electronegative. Moreover, considering the weak signal of C-Mo-Br species in Fig. 4b, it can be concluded that the hydrothermal etching strategy in this paper made an instability of -Br or -Cl, which were easily replaced by -O or -OH. Therefore, the surface of Mo_2C -CTAB is mainly terminated by -O and a little - OH/Br/Cl, and the Fermi level of Mo_2C -CTAB can be approximatively regarded as 1.09 V vs. NHE.

Photocatalyst	Catalyst amount (mg)	Sacrificial agent	Optimum co- catalyst loading	Light intensity (mW/cm ²)	H ₂ -rate (mmol g ⁻¹ h ⁻¹)	Ref.
CZS/Mo ₂ C	20	Lactic acid	20 wt.%	80	44.19	This work
CZS/Ti ₃ C ₂	10	Na ₂ SO ₃ /Na ₂ S	1 wt.%	N/A	15.0	7
CdS/Ti ₃ C ₂	20	Lactic acid	2.5 wt.%	80	14.3	8
MoS_2/Ti_3C_2	30	Methanol	30 wt.%	N/A	6.1	9
Nb ₂ C/Nb ₂ O ₅ /C	40	Methanol	51 mol.%	120	0.007	10
CdS/Nb ₂ C	10	Lactic acid	15 wt.%	N/A	5.0	11
g-C ₃ N ₄ /Ti ₂ C	50	Triethanolamine	0.4 wt.%	N/A	0.95	12
CZS/g-C ₃ N ₄	20	Na ₂ SO ₃ /Na ₂ S	32 wt.%	1.5	33.4	13
CZS/CoFe ₂ O ₄	100	Na ₂ SO ₃ /Na ₂ S	7 wt.%	48.9	0.35	14
CZS/Ni ₂ P	50	Na ₂ SO ₃ /Na ₂ S	0.3 mol%	100	41.2	15
CZS/SrTiO ₃	50	Na ₂ SO ₃ /Na ₂ S	N/A	150	25.0	16
CZS/NiB	6.6	Lactic acid	15 wt.%	N/A	8.1	17
CZS/La	N/A	Na ₂ SO ₃ /Na ₂ S	2 wt.%	N/A	1.39	18
CZS-P/Pt-PdS	10	Na ₂ SO ₃ /Na ₂ S	N/A	100	7.1	19

 Tab. S4 Comparison of the photocatalytic H₂ production performance under visible-light of CZS/Mo₂C and other state-of-the-art CZS-based photocatalysts previously reported.

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